Searcn Notes	
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Application/Control No.	Applicant(s)/Patent under Reexamination
10/518,234	SHIRAKAWA ET AL.
Examiner	Art Unit
Dung (Michael) T. Nguyen	2828

SEARCHED					
Class	Subclass	Date	Examiner		
372	6	5/31/2007	DN		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
			DATE	EXMR
East			5/31/2007	DN
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